

Description

Semicoa Semiconductors offers:

- Screening and processing per MIL-PRF-19500 Appendix E
- JAN level (2N2222AJ)
- JANTX level (2N2222AJX)
- JANTXV level (2N2222AJV)
- JANS level (2N2222AJS)
- QCI to the applicable level
- 100% die visual inspection per MIL-STD-750 method 2072 for JANTXV and JANS
- Radiation testing (total dose) upon request

Applications

- General purpose
- Low power
- NPN silicon transistor

**Features**

- Hermetically sealed TO-18 metal can
- Also available in chip configuration
- Chip geometry 0400
- Reference document: MIL-PRF-19500/255

Benefits

- Qualification Levels: JAN, JANTX, JANTXV and JANS
- Radiation testing available

Absolute Maximum Ratings		T_c = 25°C unless otherwise specified	
Parameter	Symbol	Rating	Unit
Collector-Emitter Voltage	V _{CEO}	50	Volts
Collector-Base Voltage	V _{CBO}	75	Volts
Emitter-Base Voltage	V _{EBO}	6	Volts
Collector Current, Continuous	I _C	800	mA
Power Dissipation, T _A = 25°C Derate linearly above 37.5°C	P _T	0.5 3.08	W mW/°C
Operating Junction Temperature	T _J	-65 to +200	°C
Storage Temperature	T _{STG}	-65 to +200	°C
Thermal Resistance	R _{θJA}	325	°C/W

ELECTRICAL CHARACTERISTICS

characteristics specified at $T_A = 25^\circ\text{C}$

Off Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Collector-Emitter Breakdown Voltage	$V_{(\text{BR})\text{CEO}}$	$I_C = 10 \text{ mA}$	50			Volts
Collector-Base Cutoff Current	$I_{\text{CBO}1}$	$V_{\text{CB}} = 75 \text{ Volts}$			10	μA
Collector-Base Cutoff Current	$I_{\text{CBO}2}$	$V_{\text{CB}} = 60 \text{ Volts}$			10	nA
Collector-Base Cutoff Current	$I_{\text{CBO}3}$	$V_{\text{CB}} = 60 \text{ Volts}, T_A = 150^\circ\text{C}$			10	μA
Collector-Emitter Cutoff Current	I_{CES}	$V_{\text{CE}} = 50 \text{ Volts}$			50	nA
Emitter-Base Cutoff Current	$I_{\text{EBO}1}$	$V_{\text{EB}} = 6 \text{ Volts}$			10	μA
Emitter-Base Cutoff Current	$I_{\text{EBO}2}$	$V_{\text{EB}} = 4 \text{ Volts}$			10	nA

On Characteristics

Pulse Test: Pulse Width = 300 μs , Duty Cycle $\leq 2.0\%$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
DC Current Gain	$h_{\text{FE}1}$	$I_C = 0.1 \text{ mA}, V_{\text{CE}} = 10 \text{ Volts}$	50			
	$h_{\text{FE}2}$	$I_C = 1.0 \text{ mA}, V_{\text{CE}} = 10 \text{ Volts}$	75		325	
	$h_{\text{FE}3}$	$I_C = 10 \text{ mA}, V_{\text{CE}} = 10 \text{ Volts}$	100			
	$h_{\text{FE}4}$	$I_C = 150 \text{ mA}, V_{\text{CE}} = 10 \text{ Volts}$	100		300	
	$h_{\text{FE}5}$	$I_C = 500 \text{ mA}, V_{\text{CE}} = 10 \text{ Volts}$	30			
	$h_{\text{FE}6}$	$I_C = 10 \text{ mA}, V_{\text{CE}} = 10 \text{ Volts}, T_A = -55^\circ\text{C}$	35			
Base-Emitter Saturation Voltage	$V_{\text{BEsat}1}$ $V_{\text{BEsat}2}$	$I_C = 150 \text{ mA}, I_B = 15 \text{ mA}$ $I_C = 500 \text{ mA}, I_B = 50 \text{ mA}$	0.6		1.2 2.0	Volts
Collector-Emitter Saturation Voltage	$V_{\text{CEsat}1}$ $V_{\text{CEsat}2}$	$I_C = 150 \text{ mA}, I_B = 15 \text{ mA}$ $I_C = 500 \text{ mA}, I_B = 50 \text{ mA}$			0.3 1.0	Volts

Dynamic Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Magnitude – Common Emitter, Short Circuit Forward Current Transfer Ratio	$ h_{\text{FE}} $	$V_{\text{CE}} = 20 \text{ Volts}, I_C = 20 \text{ mA}, f = 100 \text{ MHz}$	2.5			
Small Signal Short Circuit Forward Current Transfer Ratio	h_{FE}	$V_{\text{CE}} = 10 \text{ Volts}, I_C = 1 \text{ mA}, f = 1 \text{ kHz}$	50			
Open Circuit Output Capacitance	C_{OBO}	$V_{\text{CB}} = 10 \text{ Volts}, I_E = 0 \text{ mA}, 100 \text{ kHz} < f < 1 \text{ MHz}$			8	pF
Open Circuit Input Capacitance	C_{IBO}	$V_{\text{EB}} = 0.5 \text{ Volts}, I_C = 0 \text{ mA}, 100 \text{ kHz} < f < 1 \text{ MHz}$			25	pF

Switching Characteristics

Saturated Turn-Off Time	t_{off}				300	ns
Saturated Turn-On Time	t_{on}				35	ns